

## 6.4 - 8.6GHz LOW NOISE, GAIN CONTROL AMPLIFIER

G A A S M O N O L I T H I C M I C R O W A V E I C

### FEATURES

- 3.3dB noise figure
- 20dB gain
- 24dB dynamic gain control
- Good input and output matching

- Available in chip form : CHA2001-99A/00 and T-PAK package : CHA2001-C1A/00
- Economic version : CHA2001-99A/01

### APPLICATIONS

C-band radar and telecommunication receivers.

Automatic Gain control amplifiers

### DESCRIPTION

The CHA2001 is a C-band monolithic three stage LNA including a dual gate MESFET as a control element. The gain can be varied continuously from +20 to -4dB by means of a control voltage  $V_C$ .

The circuit is manufactured with the LN05 standard process : 0.5µm implanted MESFET, via holes, air bridges and electron beam gate lithography.

Chip size 2 x 1 mm<sup>2</sup>

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### ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	MIN.	MAX.	UNIT
Drain to source voltage	$V_{DS}$		5	V
Drain current	$I_{DS}$		150	mA
Drain to gate voltage	$V_{DG}$		7	V
Gain control voltage	$V_C$	-2.5	+2.5	V
Input power (CW)	$P_{in}$		15	dBm
Operating temperature range	$T_A$	-40	+80	°C
Storage temperature range	$T_{stg}$	-55	+175	°C



**ELECTRICAL CHARACTERISTICS (T<sub>amb</sub> = + 25°C) (DIE FORM)**

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Operating frequency range	f <sub>op</sub>		6.4		8.6	GHz
Small signal gain	G	(1) (2)	16	20 -4		dB
Gain flatness	ΔG	(1) (2)		± 1.5 ± 1.7	± 2.0 ± 2.5	dB
Noise figure CHA2001-99A/00 99A/01	NF	(1)		3.3 3.6	3.5 3.8	dB
Output power at 1dB gain compression (3)	P <sub>01</sub>	(1)		11		dBm
Gain Control range (3)	G <sub>CR</sub>	(1,2)	19	24		dB
Input V.S.W.R.		(1,2)		2.2 : 1	2.5 : 1	
Output V.S.W.R.		(1,2)		1.4 : 1	2.0 : 1	
Reverse isolation		(1)	-42	-45		dB
Drain current	I <sub>D</sub>	(1) (2)		60 45	80 60	mA
Drain to source voltage	V <sub>DS</sub>			3	5	V
Gate to source voltage	V <sub>GS</sub>		-2	-0.4	0	V
Gain control voltage	V <sub>C</sub>	(1) (2)		+1.5 -1.2		V

(1) V<sub>D</sub> = 3V      V<sub>G</sub> = -0.4V      V<sub>C</sub> = +1.5V for maximum gain(2) V<sub>D</sub> = 3V      V<sub>G</sub> = -0.4V      V<sub>C</sub> = -1.2V for maximum attenuation

(3) Measured on assembled die.

**ELECTRICAL CHARACTERISTICS (T<sub>amb</sub> = + 25°C) (T-PAK® FORM)**

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Operating frequency range	f <sub>op</sub>		6.4		8.6	GHz
Small signal gain	G	(1) (2)	15	19 -4		dB
Gain flatness	ΔG	(1) (2)		± 1.5 ± 1.7	± 2.0 ± 2.5	dB
Noise figure CHA2001-99A/00 99A/01	NF	(1)		3.7 4	3.9 4.2	dB
Output power at 1dB gain compression	P <sub>01</sub>	(1)	9	11		dBm
Gain Control range	G <sub>CR</sub>	(1,2)	19	24		dB
Input V.S.W.R.		(1,2)		1.8 : 1	2.2 : 1	-
Output V.S.W.R.		(1,2)		2.2 : 1	2.5 : 1	-
Reverse isolation		(1)	25	30		dB
Drain current	I <sub>D</sub>	(1) (2)		60 45	80 60	mA
Drain to source voltage	V <sub>DS</sub>			3	5	V
Gate to source voltage	V <sub>GS</sub>		-2	-0.4	0	V
Gain control voltage	V <sub>C</sub>	(1) (2)		+1.5 -1.2		V

(1) V<sub>D</sub> = 3V      V<sub>G</sub> = -0.4V      V<sub>C</sub> = +1.5V for maximum gain(2) V<sub>D</sub> = 3V      V<sub>G</sub> = -0.4V      V<sub>C</sub> = -1.2V for maximum attenuation

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## HANDLING AND BONDING PROCEDURES

### ◆ STORAGE

It is recommended that GaAs MMICs be stored in a dry nitrogen environment until die attached. Since Gallium Arsenide is a more brittle material than Silicon, special care must be taken when removing the chip from the carrier.

### ◆ DIE ATTACH

Stage temperature = 300°C (Minimize temperature and time whenever possible).

Preforms : Au/Sn (80/20)

Handling : grounded equipment and personnel.

Atmosphere : Dry nitrogen or forming gas flow over a clean die attach stage is recommended.

### ◆ BONDING

Thermal compression bonding is recommended using very pure gold wire of 25 $\mu$ m in diameter. The bonder should be properly grounded.

### ◆ PRECAUTIONS

Permanent damage to the device can result from inadequate protection against excessive voltages on the device due to static

charge build up, test equipment transients and inductive pick up. Grounding of equipment and personnel during the handling and testing of GaAs MMICs and control of the device test conditions and environment should be standard procedures.

### ◆ DICE BONDING PAD LAYOUT

#### TO READ ATTENTIVELY

The ground pads must be connected to ground very close to the chip.

## PIN ALLOCATIONS

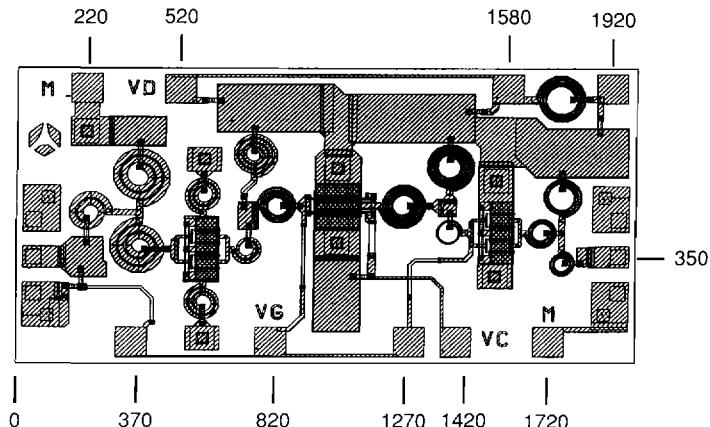
- 1- RF input
- 2- Drain supply voltage
- 3- RF output
- 4- Gate supply voltage

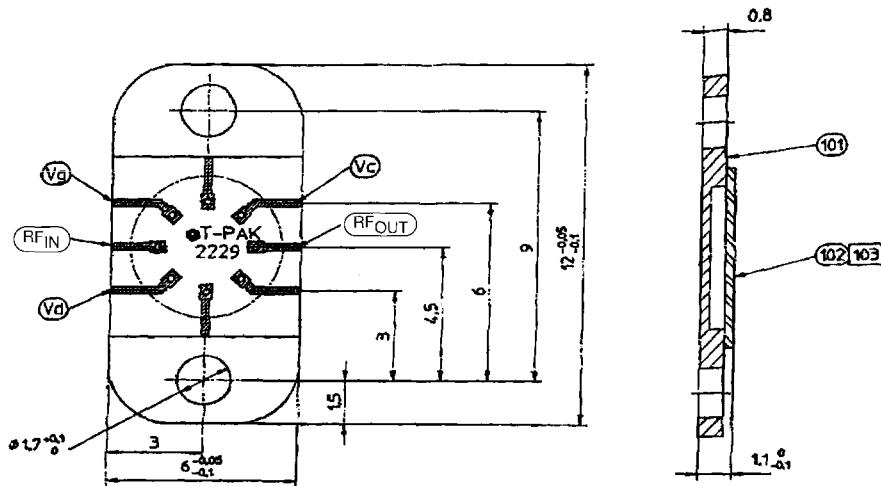
## ORDERING INFORMATIONS

CHA2001-99A/00 Chip form

CHA2001-C1E/00 T-PAK® TPS1

## CHIP LAYOUT



**T-PAK® PACKAGE DRAWING****5**

General tolerances = - 0.05

